TMP320C50KGD, TMP320LC50KGD
DIGITAL SIGNAL PROCESSOR
KNOWN GOOD DIE

SGZS008B – JULY 1996 – REVISED JUNE 1999

- 35-ns and 50-ns Single-Cycle Instruction Execution Time for 5 V Operation
- 50-ns Single-Cycle Instruction Execution Time for 3.3 V Operation
- Source-Code Compatible With All 'C1x and 'C2x Devices
- RAM-Based Operation
  - 9K-Words × 16-Bit Single-Access On-Chip Program/Data RAM
  - 1 056-Word × 16-Bit Dual-Access On-Chip Data RAM
- 2K-Word × 16-Bit On-Chip Boot ROM
- 224K-Word × 16-Bit Maximum Addressable External Memory Space (64K-Word Program, 64K-Word Data, 64K-Word I/O, and 32K-Word Global)
- 32-Bit Arithmetic Logic Unit (ALU)
  - 32-Bit Accumulator (ACC)
  - 32-Bit Accumulator Buffer (ACCB)

- 16-Bit Parallel Logic Unit (PLU)
- 16 × 16-Bit Multiplier, 32-Bit Product
- Eleven Context Switch Registers
- Two Buffers for Circular Addressing
- Full-Duplex Synchronous Serial Port
- Time-Division Multiplexed Serial Port (TDM)
- Timer With Control and Counter Registers
- 16 Software Programmable Wait-State Generators
- Divide-By-1 Clock Option
- IEEE Standard 1149.1† Test Access Port
- Operations are Fully Static
- Fabricated Using the Texas Instruments Enhanced Performance Implanted CMOS (EPIC™) 0.72-μm Technology

description

The TMP320C50KGD digital signal processor (DSP) is a high performance, 16-bit, fixed-point processor manufactured in 0.72-μm double-level metal CMOS technology. The TMP320LC50KGD has the same functionality as the 'C50KGD except for operation at 3.3 V instead of 5 V.

Texas Instruments Military Products currently employs three primary processes for the development of a known good die (KGD), one of which is applied to the TMP320C50 and TMP320LC50 devices. This process, known as hot-chuck-probe, uses a standard probed product that is tested again, this time at full data sheet specifications, in wafer form at speed and elevated temperature (85°C). Each individual die then is sawed, inspected, and packed for shipment. This flow produces a bare die that has been temperature-tested at speed and is known to be good, without having to use a temporary package.

A number of enhancements to the basic 'C2x architecture give the 'C5x a minimum 2x performance over the previous generation. A four-deep instruction pipeline, incorporating delayed branching, delayed call to subroutine, and delayed return from subroutine, allows the 'C5x to perform instructions in fewer cycles. The addition of a PLU gives the 'C5x a method of manipulating bits in data memory without using the accumulator and ALU. The 'C5x has additional shifting and scaling capability for proper alignment of multiplicands or storage of values to data memory.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

† IEEE Standard 1149.1–1990, IEEE Standard Test-Access Port and Boundary-Scan Architecture
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description (continued)

With the addition of the IDLE2 instruction, the 'C5x achieves low-power consumption. IDLE2 removes the functional clock from the internal hardware of the 'C5x that puts it into a total-sleep mode using only 5 µA. A low-logic level on an external interrupt with chip duration of at least five clock cycles ends the IDLE2 mode.

TMP Product Flow; 40 and 57 MHz

Multiprobe	dc test @ 25°C
Visual	40x
Test conditions	Per commercial data sheet
DC test	Hot chuck probe @ 85°C
AC test	Hot chuck probe @ 85°C @ Speed
Warranty	Datasheet upon shipment, 1 year

For electrical and timing specifications, see the *TMS320C5x, TMS320LC5x Digital Signal Processors* data sheet, literature number SPRS030.

Specific Die-Related Information

Die Size (approximate)	391 mils x 421 mils
Die Thickness	15.5 mils ± 1 mil
Backside Surface Finish	SIO2
Die Backside Potential	Floating
Max Allowable Die Junction Operating Temperature	175°C
Glassivation Material and Thickness	3KAOX/9KACN
Recommended Packing	GEL PAK
Die Attach Information	SILVER GLASS
Suggested Bond Wire Size	1.25 AL
Suggested Bonding Method	WEDGE
ESD Sensitivity	Class II
Max Allowable Process Temperature for Die Attach	450°C

TMP320C50/LC50 Pad Information

	PAD	XCENTER	YCENTER	PAD NAME
TOP	1	5347.4	9670.8	$\overline{\text{IAQ}}$
	2	5161.8	9670.8	$\overline{\text{TRST}}$
	3	4908.6	9670.8	V_{SS1}
	4	4773.6	9670.8	V_{SS2}
	5	4573.4	9670.8	MP/$\overline{\text{MC}}$
	6	4139.3	9670.8	D15
	7	3851.3	9670.8	D14
	8	3515.3	9670.8	D13
	9	3272.3	9670.8	D12
	10	3024.8	9670.8	D11
	11	2777.3	9670.8	D10
	12	2421.0	9670.8	D9
	13	2121.1	9670.8	D8
	14	1702.6	9670.8	V_{DD1}
	15	1567.6	9670.8	V_{DD2}
LEFT	16	106.3	8552.8	V_{SS3}
	17	106.3	8417.8	V_{SS4}
	18	106.3	7859.8	D7
	19	106.3	7616.8	D6
	20	106.3	7321.3	D5
	21	106.3	7096.3	D4
	22	106.3	6871.3	D3
	23	106.3	6646.3	D2
	24	106.3	6323.9	D1
	25	106.3	6098.9	D0
	26	106.3	5818.7	TMS
	27	106.3	5498.0	V_{DD3}
	28	106.3	5363.0	V_{DD4}
	29	106.3	4942.2	TCK
	30	106.3	4764.3	NC
	31	106.3	4601.2	V_{SS5}
	32	106.3	4466.2	V_{SS6}
	33	106.3	4041.0	$\overline{\text{INT1}}$
	34	106.3	3789.2	$\overline{\text{INT2}}$
	35	106.3	3537.4	$\overline{\text{INT3}}$
	36	106.3	3201.4	$\overline{\text{INT4}}$
	37	106.3	2949.6	$\overline{\text{NMI}}$
	38	106.3	2697.8	DR
	39	106.3	2445.9	$\overline{\text{TDR}}$
	40	106.3	2035.1	FSR

	PAD	XCENTER	YCENTER	PAD NAME
	41	106.3	1783.3	CLKR
	42	106.3	1353.6	V_{DD5}
	43	106.3	1218.6	V_{DD6}
BOTTOM	44	1513.4	106.3	V_{SS7}
	45	1648.4	106.3	V_{SS8}
	46	2128.3	106.3	A0
	47	2403.3	106.3	A1
	48	2637.3	106.3	A2
	49	2912.2	106.3	A3
	50	3132.7	106.3	A4
	51	3407.7	106.3	A5
	52	3628.2	106.3	A6
	53	3903.1	106.3	A7
	54	4123.6	106.3	A8
	55	4398.6	106.3	A9
	56	4569.6	106.3	V_{DD7}
	57	4704.6	106.3	V_{DD8}
	58	4896.7	106.3	TDI
	59	5319.8	106.3	V_{SS9}
	60	5454.8	106.3	V_{SS10}
	61	5646.0	106.3	CLKMOD1
	62	5886.6	106.3	A10
	63	6161.6	106.3	A11
	64	6527.3	106.3	A12
	65	6802.3	106.3	A13
	66	7036.3	106.3	A14
	67	7311.2	106.3	A15
	68	8202.2	106.3	V_{DD9}
	69	8337.2	106.3	V_{DD10}
	70	8649.0	106.3	$\overline{\text{RD}}$
	71	9195.5	106.3	$\overline{\text{WE}}$
RIGHT	72	10274.3	1253.8	V_{SS11}
	73	10274.3	1388.8	V_{SS12}
	74	10274.3	1902.2	$\overline{\text{DS}}$
	75	10274.3	2236.6	$\overline{\text{IS}}$
	76	10274.3	2524.8	$\overline{\text{PS}}$
	77	10274.3	2882.6	$\overline{\text{RW}}$
	78	10274.3	3168.8	$\overline{\text{STRB}}$
	79	10274.3	3365.0	$\overline{\text{BR}}$
	80	10274.3	3625.7	NC

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TMP320C50/LC50 Pad Information (Continued)

	PAD	XCENTER	YCENTER	PAD NAME
	81	10274.3	3795.5	CLKIN2
	82	10274.3	3950.6	X2/CLKIN
	83	10274.3	4126.6	X1
	84	10274.3	4296.2	NC
	85	10274.3	4459.4	V_{DD11}
	86	10274.3	4594.4	V_{DD12}
	87	10274.3	4766.7	TDO
	88	10274.3	5085.1	V_{SS13}
	89	10274.3	5220.1	V_{SS14}
	90	10274.3	5375.3	CLKMD2
	91	10274.3	5579.4	FSX
	92	10274.3	5866.1	TFSX/TFRM
	93	10274.3	6086.8	DX
	94	10274.3	6379.1	TDX
	95	10274.3	6599.8	HOLDA
	96	10274.3	6820.5	XF
	97	10274.3	7180.3	CLKOUT1
	98	10274.3	7558.5	IACK
	99	10274.3	8089.5	V_{DD13}
	100	10274.3	8224.5	V_{DD14}
	101	10274.3	8724.3	NC
	102	10274.3	8859.3	NC
TOP-R	103	9201.4	9670.8	EMU0
	104	8796.6	9670.8	EMU1/OFF
	105	8540.1	9670.8	$\overline{V}_{SS15}$
	106	8405.1	9670.8	V_{SS16}
	107	7927.9	9670.8	TOUT
	108	7690.0	9670.8	TCLKX
	109	7456.5	9670.8	CLKX
	110	7133.8	9670.8	TFSR/TADD
	111	6956.1	9670.8	TCLKR
	112	6771.8	9670.8	RS
	113	6587.5	9670.8	READY
	114	6403.1	9670.8	HOLD
	115	6016.9	9670.8	BIO
	116	5780.7	9670.8	V_{DD15}
	117	5645.7	9670.8	V_{DD16}

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MECHANICAL DATA

MOUNT AND BOND

PAD #1

TMS320C50BS
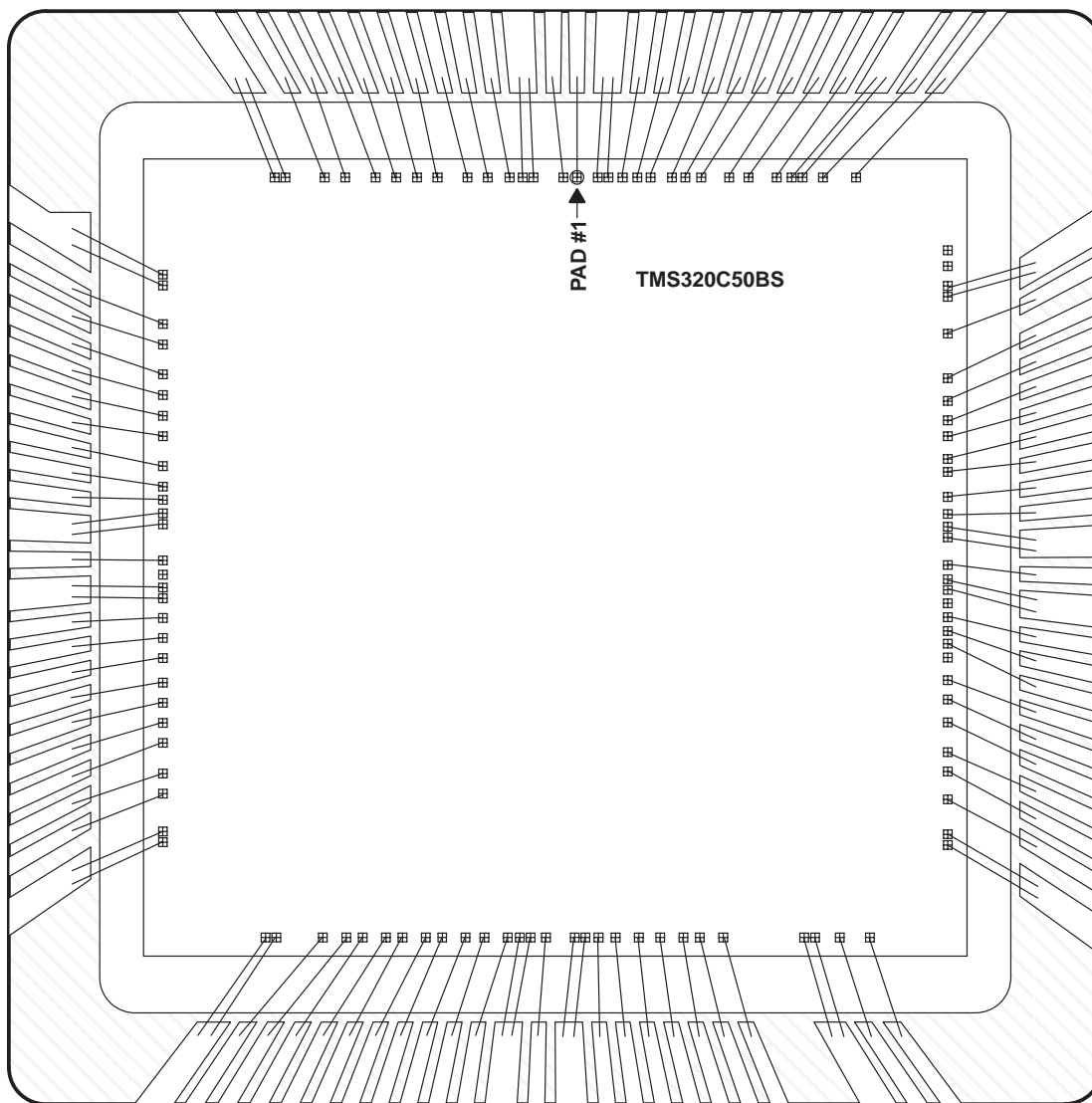
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